

<b>Notice of References Cited</b>		Application/Control No. 10/501,303	Applicant(s)/Patent Under Reexamination SEKIYA ET AL.	
		Examiner Mark Halpern	Art Unit 1791	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,267,842	07-2001	Ona et al.	162/135
*	C	US-2001/0037529	11-2001	Igarashi et al.	8/115.51
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	K	US-			
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#### NON-PATENT DOCUMENTS

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